

# Power MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	650					
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V	2.1				
Q <sub>g</sub> (Max.) (nC)	48					
Q <sub>gs</sub> (nC)	12					
Q <sub>gd</sub> (nC)	19					
Configuration	Single					

#### **FEATURES**

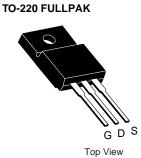
• Low Gate Charge Qg Results in Simple Drive Requirement

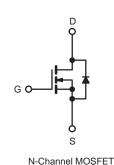


RoHS

COMPLIANT

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS T<sub>C</sub> = 25 °C, unless otherwise noted PARAMETER SYMBOL LIMIT UNIT **Drain-Source Voltage** V<sub>DS</sub> 650 V ± 30 Gate-Source Voltage V<sub>GS</sub>  $T_C = 25 \degree C$ Continuous Drain Currente 4.5 V<sub>GS</sub> at 10 V  $I_D$  $T_{C} = 100 \,^{\circ}C$ **Continuous Drain Current** 4.2 А Pulsed Drain Current<sup>a</sup> I<sub>DM</sub> 18 Linear Derating Factor 0.48 W/°C E<sub>AS</sub> Single Pulse Avalanche Energy<sup>b</sup> 325 mJ Repetitive Avalanche Currenta 4 А  $I_{AR}$ Repetitive Avalanche Energy<sup>a</sup>  $\mathsf{E}_{\mathsf{AR}}$ 6 mJ Maximum Power Dissipation T<sub>C</sub> = 25 °C  $\mathsf{P}_\mathsf{D}$ 30 W Peak Diode Recovery dV/dtc dV/dt 2.8 V/ns Operating Junction and Storage Temperature Range - 55 to + 150 T<sub>J</sub>, T<sub>stg</sub> °C Soldering Recommendations (Peak Temperature)<sup>d</sup> for 10 s 300 10 lbf · in Mounting Torque 6-32 or M3 screw 1.1 N · m

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T<sub>J</sub> = 25 °C, L = 24 mH, R<sub>G</sub> = 25  $\Omega$ , I<sub>AS</sub> = 3.2 A (see fig. 12).

- c.  $I_{SD} \le 3.2$  Å, dI/dt  $\le 90$  Å/µs,  $V_{DD} \le V_{DS}$ ,  $T_J \le 150$  °C.
- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RA	TINGS									
PARAMETER	SYMBOL	TYP. MAX.			UNIT					
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 65			°C/W					
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 2.1								
<b>SPECIFICATIONS</b> $T_J = 25 \text{ °C}$ , unless otherwise noted										
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT			
Static						•				
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	= 0 V, I <sub>D</sub> = 2	50 µA	650	-	-	V		
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	l <sub>D</sub> = 1 mA <sup>d</sup>	-	670	-	mV/°C		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 2	250 µA	2.0	-	4.0	V		
Gate-Source Leakage	I <sub>GSS</sub>	,	$V_{\rm GS} = \pm 30$	V	-	-	± 100	nA		
Zara Cata Valtaga Drain Current	1	V <sub>DS</sub> =	V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V = 520 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	<sub>6</sub> = 0 V	-	-	25	μA		
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 520 V		, T <sub>J</sub> = 125 °C	-	-	250			
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub>	= 3.1 A <sup>b</sup>	-	-	2.1	Ω		
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> :	= 50 V, I <sub>D</sub> =	3.1 A	3.9	-	-	S		
Dynamic										
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		-	1417	-	-			
Output Capacitance	C <sub>oss</sub>			-	177	-				
Reverse Transfer Capacitance	C <sub>rss</sub>			-	7.0	-				
Output Capacitance	6		$V_{DS} = 1.0$	V, f = 1.0 MHz	-	1912	-	pF		
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 V$	V <sub>DS</sub> = 520 V, f = 1.0 MHz	-	48	-	]			
Effective Output Capacitance	Coss eff.		$V_{DS} = 0 V \text{ to } 520 V^{c}$		-	84	-	1		
Total Gate Charge	Qg				-	-	48			
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 \text{ V}$ $I_D = 3.2 \text{ A}, V_{DS} =$		-		12	nC			
Gate-Drain Charge	Q <sub>gd</sub>		see fig. 6 and 13 <sup>b</sup>		-	-	19	1		
Turn-On Delay Time	t <sub>d(on)</sub>				-	14	-			
Rise Time	t <sub>r</sub>	$V_{DD} = 325 \text{ V}, I_D = 3.2 \text{ A} \\ R_G = 9.1 \Omega, R_D = 62 \Omega, \\ \text{see fig. } 10^{\text{b}}$		-	20	-	- ns			
Turn-Off Delay Time	t <sub>d(off)</sub>			-	34	-				
Fall Time	t <sub>f</sub>			-	18	-				
Drain-Source Body Diode Characteristic	cs									
Continuous Source-Drain Diode Current	١ <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4	A			
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	21				
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25 \text{ °C}, I_S = 3.2 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.5	V			
Body Diode Reverse Recovery Time	t <sub>rr</sub>			-	493	739	ns			
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = 3.2 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}^{b}$			-	2.1	3.2	μC		
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and L				L <sub>D</sub> )				

#### Notes

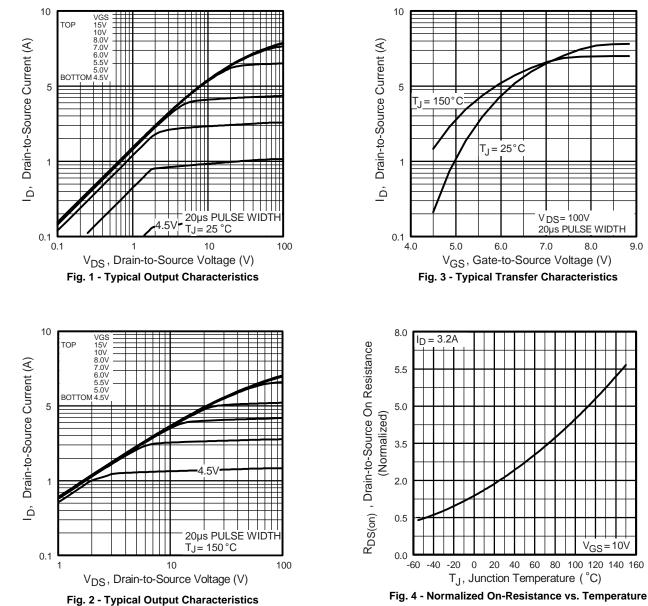
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %. c. C<sub>oss</sub> eff. is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 % to 80 % V<sub>DS</sub>.

d. t = 60 s, f = 60 Hz.



9.0



#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

### **VBMB165R04**

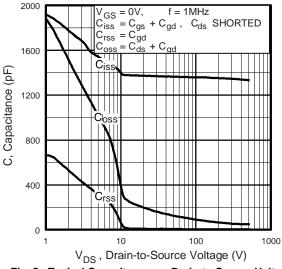


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

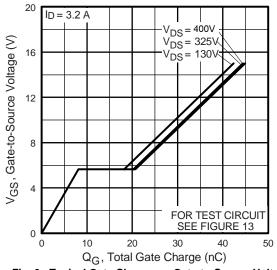
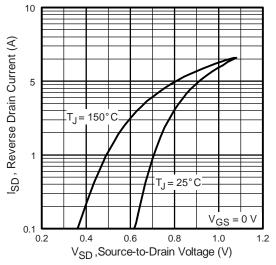


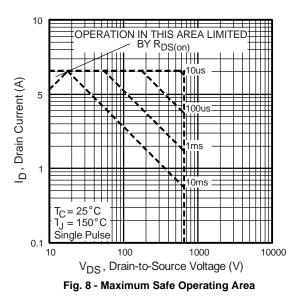
Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



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Fig. 7 - Typical Source-Drain Diode Forward Voltage



## **VBMB165R04**



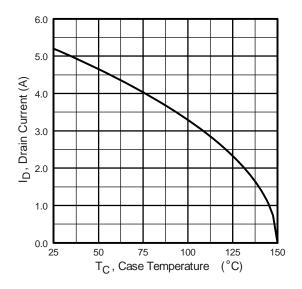


Fig. 9 - Maximum Drain Current vs. Case Temperature

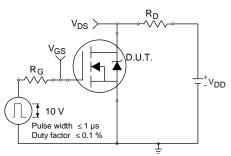


Fig. 10a - Switching Time Test Circuit

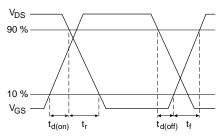
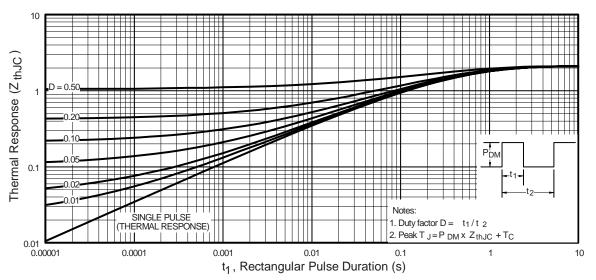


Fig. 10b - Switching Time Waveforms





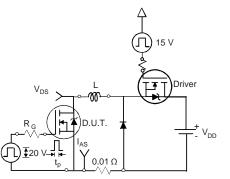
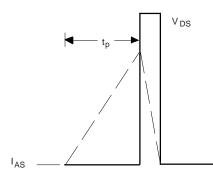
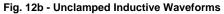


Fig. 12a - Unclamped Inductive Test Circuit





### VBMB165R04



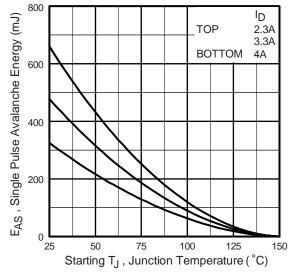


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

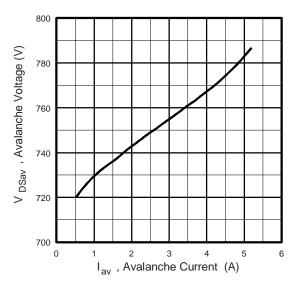


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

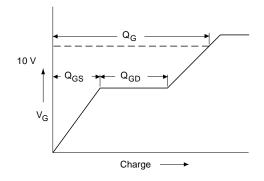


Fig. 13a - Basic Gate Charge Waveform

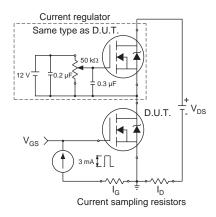
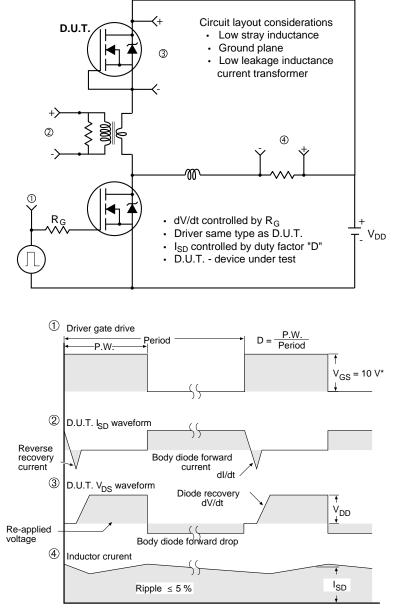


Fig. 13b - Gate Charge Test Circuit





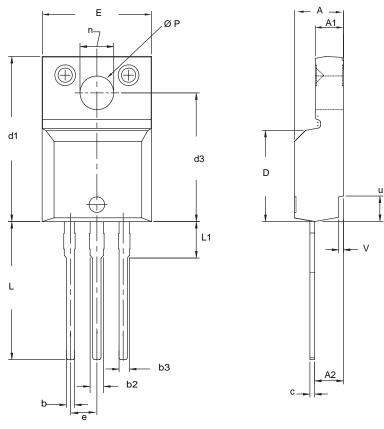
Peak Diode Recovery dV/dt Test Circuit

\*  $V_{GS}$  = 5 V for logic level devices

Fig. 14 - For N-Channel



### **TO-220 FULLPAK (HIGH VOLTAGE)**



	MILLIMETERS		INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
C	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
E	10.360	10.630	0.408	0.419	
е	2.54 BSC		0.100 BSC		
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.138	
n	6.050	6.150	0.238	0.242	
Ø P	3.050	3.450	0.120	0.136	
u	2.400	2.500	0.094	0.098	
V	0.400	0.500	0.016	0.020	
ECN: X09-0126-Rev. B, 2 DWG: 5972	26-Oct-09				

#### Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet  $C_{pk} > 1.33$ . 4. All dimensions include burrs and plating thickness.

5. No chipping or package damage.



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